

Search Notes

Application/Control No.

10/644,182

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	180	6/7/05	JLC
	105		
	186		
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	143		
	153,1		
	155		
	157,18		
	158,12		
312	257,1		
	265,1		
	265,2		
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290	180		
	188,1		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
<i>Front & back. Citations for prior art</i>	6/7/05	JLC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner